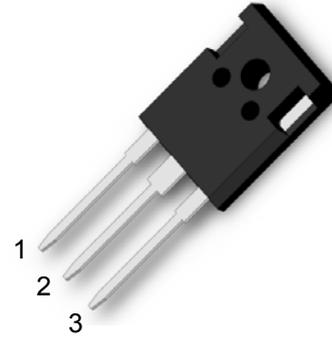


PRODUCT FEATURES

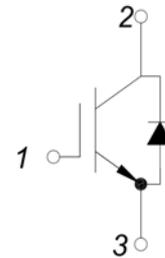
- IGBT chip in trench FS-technology
- Low switching losses
- $V_{CE(sat)}$ with positive temperature coefficient
- Fast switching and short tail current
- Free wheeling diodes with fast and soft reverse recovery



APPLICATIONS

- High frequency switching application
- Medical applications
- Motion/servo control
- UPS systems

1.Gate
2.Collector
3.Emitter



Type	V_{CES}	I_C	$V_{CE(sat)}$ $T_J=25^\circ C$	T_{Jmax}	Marking	Package
MM40G3T120B	1200V	40A	1.9V	175°C	MM40G3T120B	TO-247

ABSOLUTE MAXIMUM RATINGS($T_C=25^\circ C$ unless otherwise specified)

Symbol	Parameter/Test Conditions	Values	Unit
V_{CES}	Collector Emitter Voltage	$T_J=25^\circ C$	1200
V_{GES}	Gate Emitter Voltage		± 20
I_C	DC Collector Current	$T_C=25^\circ C$	70
		$T_C=110^\circ C$	40
I_{Cpuls}	Pulsed collector current, tp limited by T_{Jmax}		140
P_{tot}	Power Dissipation Per IGBT		395
V_{RRM}	Repetitive Reverse Voltage	$T_J=25^\circ C$	1200
$I_{F(AV)}$	Average Forward Current	$T_C=95^\circ C$	40
I_{Fpuls}	Diode pulsed current, tp limited by T_{Jmax}		80
T_{Jmax}	Max. Junction Temperature		175
T_{Jop}	Operating Temperature		-40~175
T_{stg}	Storage Temperature		-55~150
Torque	to heatsink	Recommended (M3)	1.1
Weight			8

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MM40G3T120B

IGBT

ELECTRICAL CHARACTERISTICS ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter/Test Conditions		Min.	Typ.	Max.	Unit
$V_{GE(th)}$	Gate Emitter Threshold Voltage	$V_{CE}=V_{GE}, I_C=1\text{mA}$	5.0	5.8	6.5	V
$V_{CE(sat)}$	Collector Emitter Saturation Voltage	$I_C=40\text{A}, V_{GE}=15\text{V}, T_J=25^\circ\text{C}$		1.9	2.35	
		$I_C=40\text{A}, V_{GE}=15\text{V}, T_J=125^\circ\text{C}$		2.25		
		$I_C=40\text{A}, V_{GE}=15\text{V}, T_J=150^\circ\text{C}$		2.35		
I_{CES}	Collector Leakage Current	$V_{CE}=1200\text{V}, V_{GE}=0\text{V}, T_J=25^\circ\text{C}$			100	μA
		$V_{CE}=1200\text{V}, V_{GE}=0\text{V}, T_J=150^\circ\text{C}$			10	mA
I_{GES}	Gate Leakage Current	$V_{CE}=0\text{V}, V_{GE}=\pm 15\text{V}, T_J=25^\circ\text{C}$	-400		400	nA
Q_g	Gate Charge	$V_{CE}=600\text{V}, I_C=40\text{A}, V_{GE}=15\text{V}$		210		nC
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, V_{GE}=0\text{V}, f=1\text{MHz}$		2.8		nF
C_{res}	Reverse Transfer Capacitance				110	pF
$t_{d(on)}$	Turn on Delay Time	$V_{CC}=600\text{V}, I_C=40\text{A}$ $R_G=20\Omega,$ $V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=25^\circ\text{C}$		30	ns
			$T_J=125^\circ\text{C}$		35	ns
			$T_J=150^\circ\text{C}$		40	ns
t_r	Rise Time	$V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=25^\circ\text{C}$		40	ns
			$T_J=125^\circ\text{C}$		45	ns
			$T_J=150^\circ\text{C}$		45	ns
$t_{d(off)}$	Turn off Delay Time	$V_{CC}=600\text{V}, I_C=40\text{A}$ $R_G=20\Omega,$ $V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=25^\circ\text{C}$		250	ns
			$T_J=125^\circ\text{C}$		290	ns
			$T_J=150^\circ\text{C}$		310	ns
t_f	Fall Time	$V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=25^\circ\text{C}$		100	ns
			$T_J=125^\circ\text{C}$		150	ns
			$T_J=150^\circ\text{C}$		180	ns
E_{on}	Turn on Energy	$V_{CC}=600\text{V}, I_C=40\text{A}$ $R_G=20\Omega,$ $V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=125^\circ\text{C}$		4.9	mJ
			$T_J=150^\circ\text{C}$		5.4	mJ
E_{off}	Turn off Energy	$V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=125^\circ\text{C}$		4.2	mJ
			$T_J=150^\circ\text{C}$		4.7	mJ
I_{SC}	Short Circuit Current	$t_{psc} \leq 10\mu\text{s}, V_{GE}=15\text{V}$ $T_J=125^\circ\text{C}, V_{CC}=600\text{V}$		150		A
R_{thJC}	Junction to Case Thermal Resistance (Per IGBT)				0.35	K/W

Anti-Parallel Diode

ELECTRICAL CHARACTERISTICS ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter/Test Conditions		Min.	Typ.	Max.	Unit
V_F	Forward Voltage	$I_F=40\text{A}, V_{GE}=0\text{V}, T_J=25^\circ\text{C}$		2.05	2.55	V
		$I_F=40\text{A}, V_{GE}=0\text{V}, T_J=125^\circ\text{C}$		1.85		
		$I_F=40\text{A}, V_{GE}=0\text{V}, T_J=150^\circ\text{C}$		1.75		
t_{rr}	Reverse Recovery Time	$I_F=40\text{A}, V_R=600\text{V}$ $di_F/dt=-850\text{A}/\mu\text{s}$ $T_J=150^\circ\text{C}$		350		ns
I_{RRM}	Max. Reverse Recovery Current			39.5		A
Q_{RR}	Reverse Recovery Charge			5		μC
E_{rec}	Reverse Recovery Energy			1.85		mJ
R_{thJCD}	Junction to Case Thermal Resistance (Per Diode)				0.7	K/W

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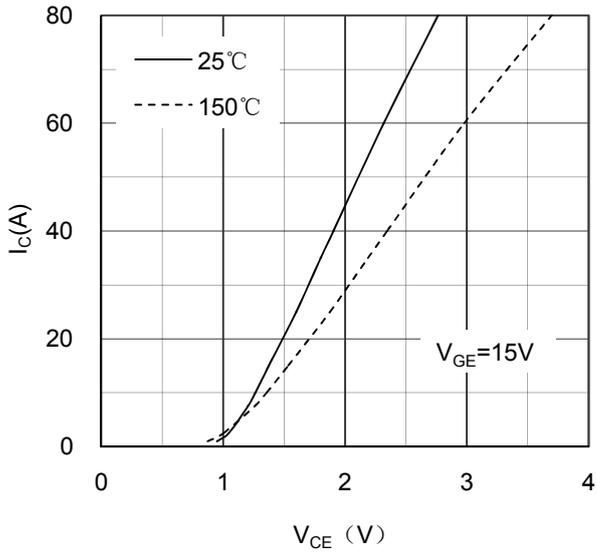


Figure 1. Typical Output Characteristics IGBT

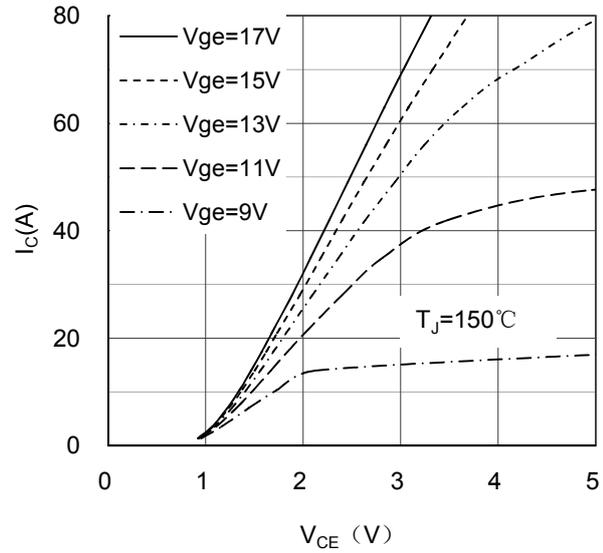


Figure 2. Typical Output Characteristics IGBT

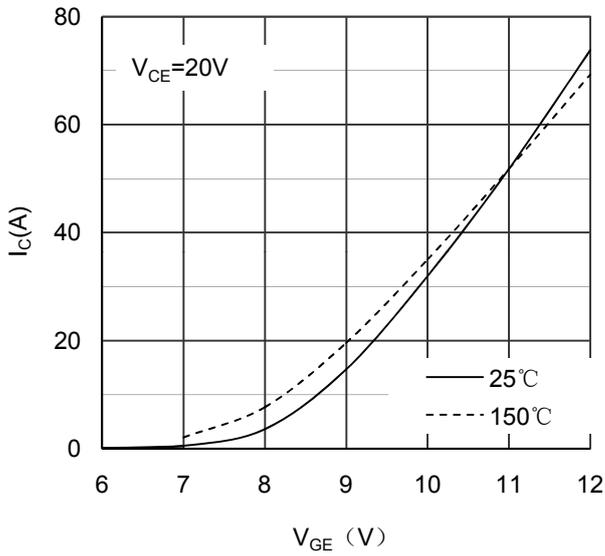


Figure 3. Typical Transfer characteristics IGBT

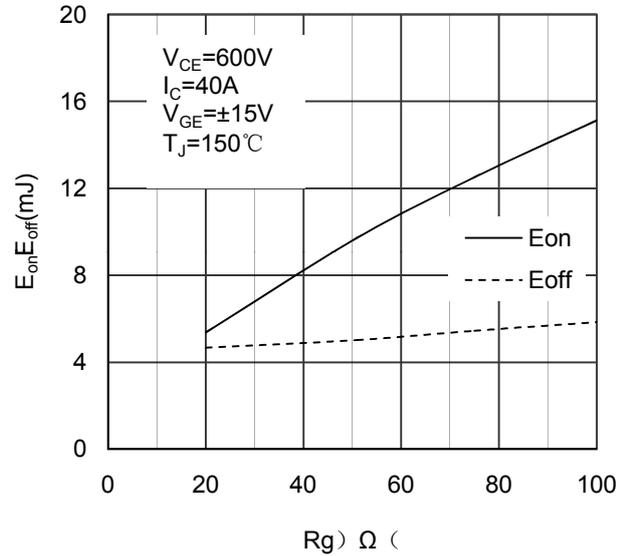


Figure 4. Switching Energy vs Gate Resistor IGBT

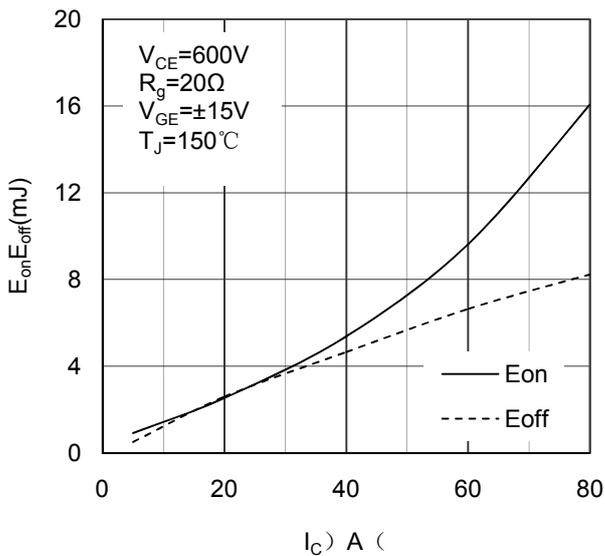


Figure 5. Switching Energy vs Collector Current IGBT

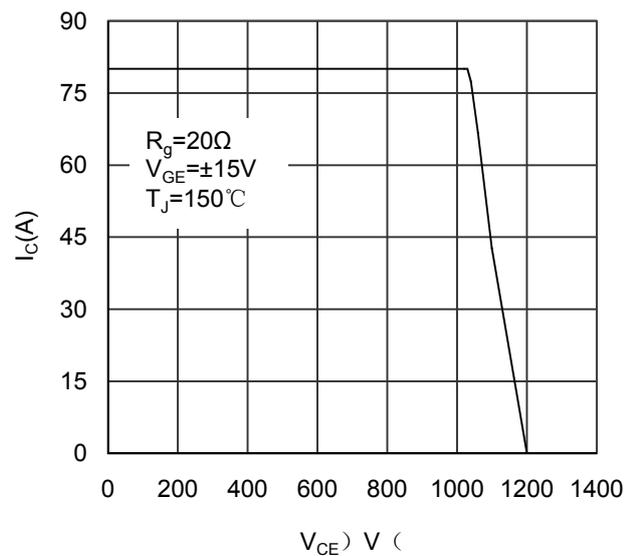


Figure 6. Reverse Biased Safe Operating Area IGBT

MM40G3T120B

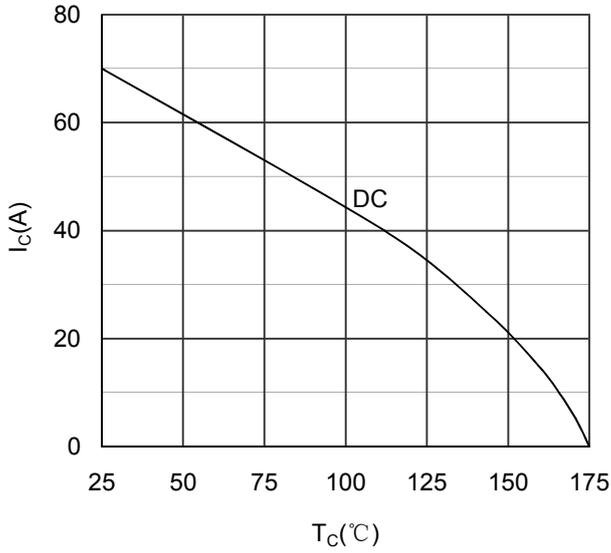


Figure 7. Collector Current vs Case temperature IGBT

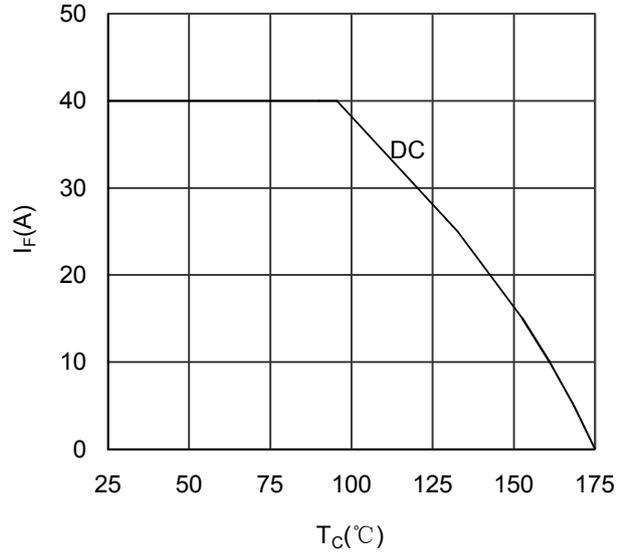


Figure 8. Forward current vs Case temperature Diode

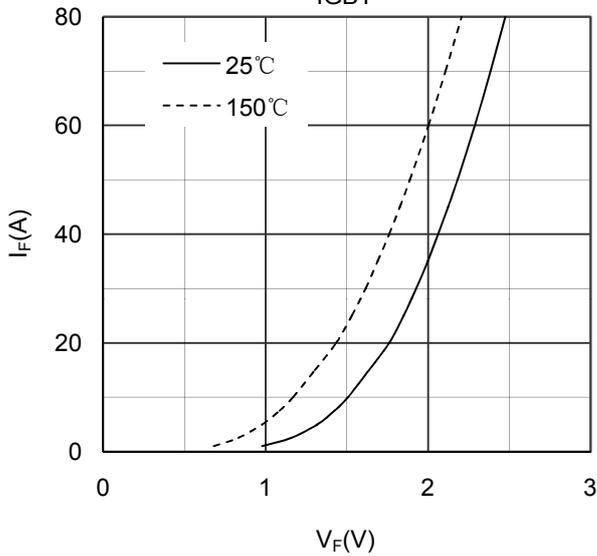


Figure 9. Diode Forward Characteristics Diode

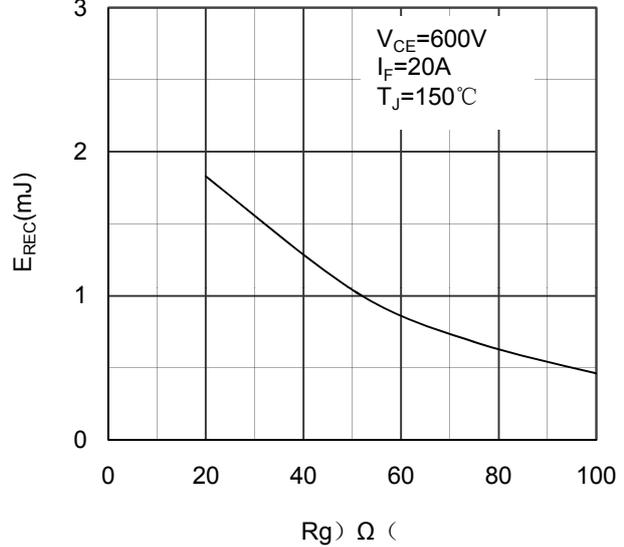


Figure 10. Switching Energy vs Gate Resistor Diode

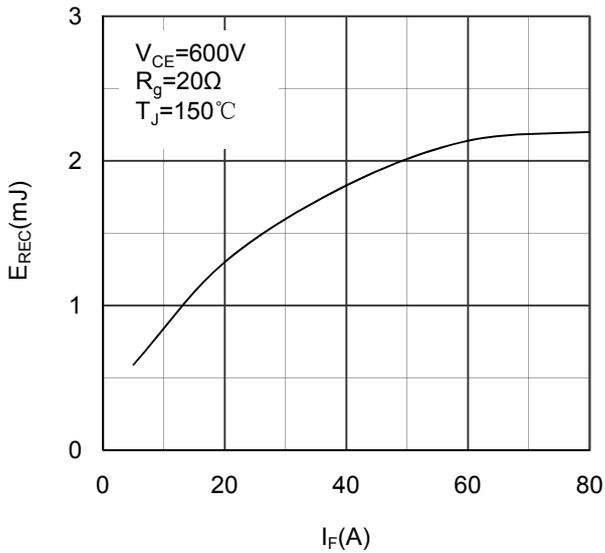


Figure 11. Switching Energy vs Forward Current Diode

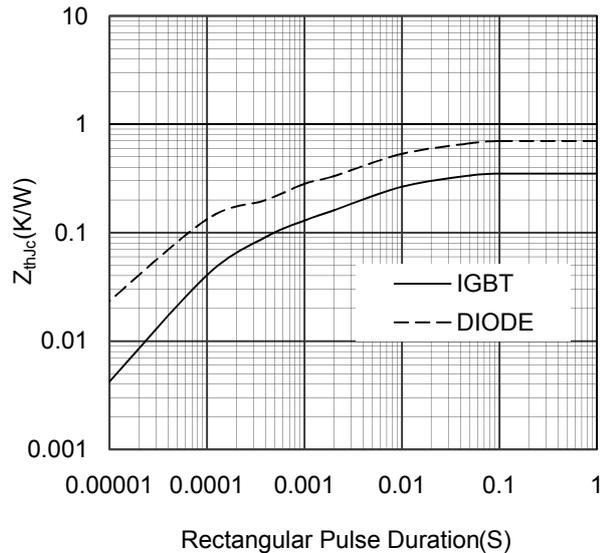
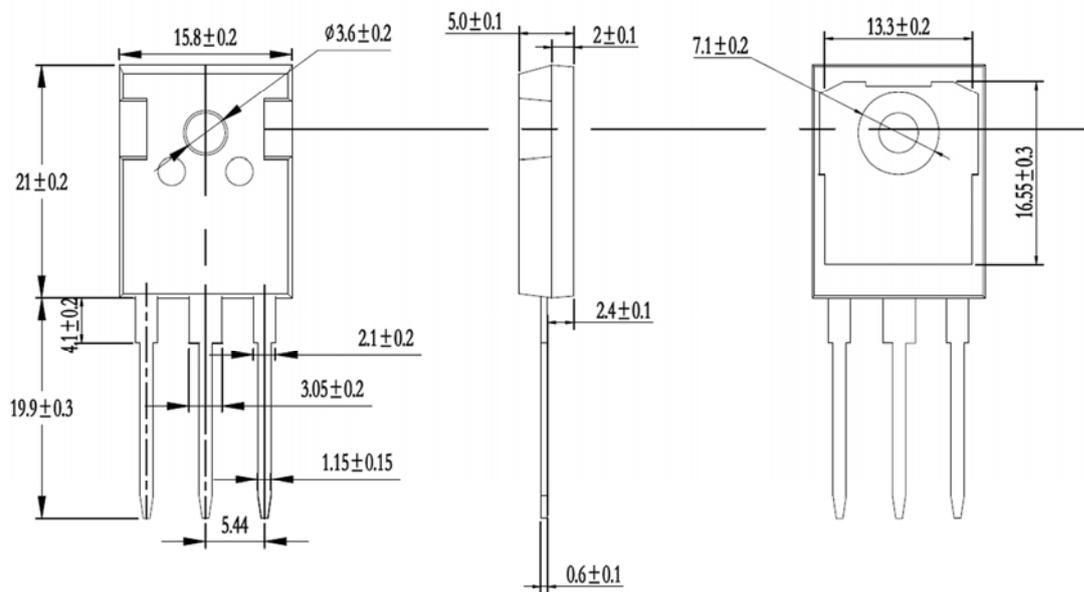


Figure 12. Transient Thermal Impedance of Diode and IGBT



Dimensions in (mm)
Figure 13. Package Outline